

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination KANAZAWA ET AL.	
		Examiner Shun Lee	Art Unit 2884	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,781,135 B2	08-2004	Berger, Kurt W.	250/372
	B	US-			
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	D	US-			
	E	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Stuik et al. Absolute calibration of a multilayer-based XUV diagnostic, Nuclear Instruments & Methods in Physics Research A, Vol. 492, no. 1-2 (11 October 2002), pp. 305-316.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.